

## **Ion tracks in mica studied with scanning force microscopy using force modulation**

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Aiming at an improved understanding of heavy-ion track formation we have imaged latent tracks in mica by means of scanning force microscopy. Studies based on *lateral* force microscopy characterized the track cross sections as amorphized zones with increased friction. In the present contribution we report on further measurements performed by operating the microscope in the mode of force modulation. The tracks, imaged by lock-in filtered signal detection, appear as areas which are softer than the undamaged surroundings. Within the experimental errors the track diameters obtained from the two experiments are in good agreement.